

Issue Classification			Application/Control No.	Applicant(s)/Patent under Reexamination
			10/620,532	FARNHAM ET AL.
			Examiner	Art Unit
			Sean E. Aeder, Ph.D.	1642

ISSUE CLASSIFICATION			
ORIGINAL		CROSS REFERENCE(S)	
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)
530	350	424	185.1
INTERNATIONAL CLASSIFICATION			
C	0	7	K 1/00
A	6	1	K 39/00
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			/

Sean E Aeder (Assistant Examiner) <i>[Signature]</i> (Date)		JEFFREY SIEW JEFFREY SIEW SUPERVISORY PATENT EXAMINER Jeffrey Siew (Primary Examiner) <i>[Signature]</i> 6/19/08 (Date)	Total Claims Allowed: 4
Kim Downing (Legal Instruments Examiner) <i>[Signature]</i> (Date)			O.G. Print Claim(s) first

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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